

CY7C024E/CY7C0241E CY7C025E/CY7C0251E

$4 \text{ K} \times 16/18 \text{ and } 8 \text{ K} \times 16/18$ Dual-Port Static RAM with SEM, INT, BUSY

Features

- True dual-ported memory cells that allow simultaneous reads of the same memory location
- 4 K × 16 organization (CY7C024E)
- 4 K × 18 organization (CY7C0241E)
- 8 K × 16 organization (CY7C025E)
- 8 K × 18 organization (CY7C0251E)
- 0.35-µ complementary metal oxide semiconductor (CMOS) for optimum speed and power
- High-speed access: 15 ns
- Low operating power: I_{CC} = 180 mA (typ), I_{SB3} = 0.05 mA (typ)
- Fully asynchronous operation
- Automatic power-down
- Expandable data bus to 32/36 bits or more using master/slave chip select when using more than one device
- On-chip arbitration logic
- Semaphores included to permit software handshaking between ports
- INT flag for port-to-port communication
- Separate upper-byte and lower-byte control
- Pin select for master or slave
- Available in Pb-free 100-pin thin quad flatpack (TQFP) package

Functional Description

The CY7C024E/CY7C0241E and CY7C025E/CY7C0251E are low-power CMOS 4K × 16/18 and 8K × 16/18 dual-port static RAMs. Various arbitration schemes are included on the CY7C024E/CY7C0241E and CY7C025E/CY7C0251E to handle situations when multiple processors access the same piece of data. Two ports are provided, permitting independent, asynchronous access for reads and writes to any location in memory. The CY7C024E/CY7C0241E and CY7C025E/CY7C0251E can be used as standalone 16 or 18-bit dual-port static RAMs or multiple devices can be combined to function as a 32-/36-bit or wider master/ slave dual-port static RAM. An M/S pin is provided for implementing 32-/36-bit or wider memory applications without the need for separate master and slave devices or additional discrete logic. Application areas include interprocessor/multiprocessor designs, communications status buffering, and dual-port video/graphics memory.

Each port has independent control pins: Chip Enable (\overline{CE}), Read or Write Enable (R/W), and Output Enable (\overline{OE}). Two flags are provided on each port (BUSY and INT). BUSY signals that the port is trying to access the same location currently being accessed by the other port. The Interrupt Flag (INT) permits communication between ports or systems by means of a mail box. The semaphores are used to pass a flag, or token, from one port to the other to indicate that a shared resource is in use. The semaphore logic is comprised of eight shared latches. Only one side can control the latch (semaphore) at any time. Control of a semaphore indicates that a shared resource is in use. An automatic pow<u>er</u>-down feature is controlled independently on each port by a CE pin.

The CY7C024E/CY7C0241E and CY7C025E/CY7C0251E are available in 100-pin Pb-free TQFP.

Selection Guide

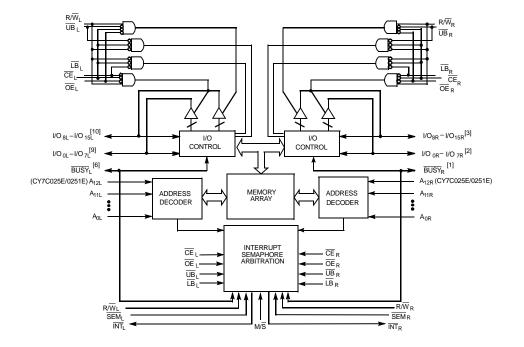
Parameter	-15	-25	-55
Maximum access time (ns)	15	25	55
Typical operating current (mA)	190	170	150
Typical standby current for I _{SB1} (mA)	50	40	20

198 Champion Court

San Jose, CA 95134-1709 • 408-943-2600 Revised August 13, 2013



Logic Block Diagram



- 1. BUSY is an output in master mode and an input in slave mode. 2. $I/O_0 I/O_8$ on the CY7C0241E/CY7C0251E. 3. $I/O_9 I/O_{17}$ on the CY7C0241E/CY7C0251E.



CY7C024E/CY7C0241E CY7C025E/CY7C0251E

Contents

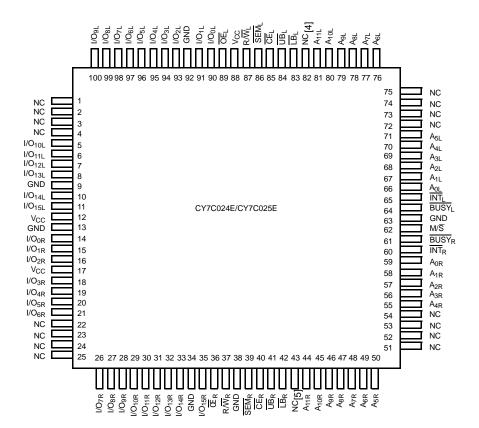
Pin Configurations	4
Pin Definitions	5
Architecture	6
Functional Description	6
Write Operation	6
Read Operation	6
Interrupts	6
Busy	
Master/Slave	6
Semaphore Operation	6
Maximum Ratings	9
Operating Range	9
Electrical Characteristics	9
Capacitance	10
Data Retention Mode	10
Data Retention Timing	10
Switching Characteristics	11
Switching Waveforms	13

Ordering Information19
4 K × 16 Dual-Port SRAM
8 K × 16 Dual-Port SRAM19
4 K × 18 Dual-Port SRAM 19
8 K × 18 Dual-Port SRAM 19
Ordering Code Definitions19
Package Diagrams
Acronyms
Document Conventions
Units of Measure21
Document History Page22
Sales, Solutions, and Legal Information
Worldwide Sales and Design Support
Products
PSoC® Solutions23
Cypress Developer Community23
Technical Support23



Pin Configurations

Figure 1. 100-Pin TQFP (Top View)

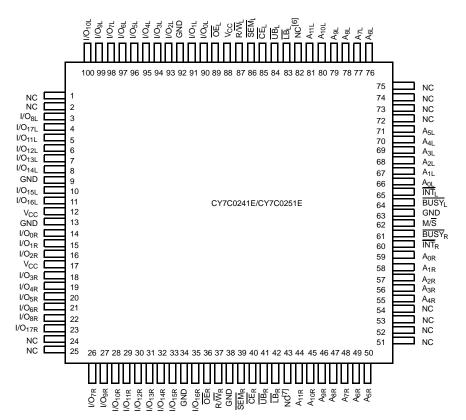


Notes

A. A_{12L} on the CY7C025E/CY7C0251E.
 A_{12R} on the CY7C025E/CY7C0251E.







Pin Definitions

Left Port	Right Port	Description
CEL	CE _R	Chip enable
R/WL	R/W _R	Read/write enable
OEL	OE _R	Output enable
A _{0L} -A _{11/12L}	A _{0R} -A _{11/12R}	Address
I/O _{0L} -I/O _{15/17L}	I/O _{0R} -I/O _{15/17R}	Data bus input/output
SEML	SEM _R	Semaphore enable
UBL	UB _R	Upper byte select
LBL	LB _R	Lower byte select
INTL	INT _R	Interrupt flag
BUSY _L ^[8]	BUSY _R ^[8]	Busy flag
M/S		Master or slave select
V _{CC}		Power
GND		Ground

Notes

6. A_{12L} on the CY7C025E/CY7C0251E.

7. A_{12R} on the CY7C025E/CY7C0251E.

8. BUSY is an output in master mode and an input in slave mode.



Architecture

The CY7C024E/CY7C0241E and CY7C025E/CY7C0251E consist of an array of 4 K words of 16/18 bits each and 8 K words of 16/18 bits each of <u>dual-port RAM</u> cells, I/O and address lines, and control signals (CE, OE, R/W). These control pins permit independent access for reads or writes to any location in memory. To handle simultaneous writes/reads to the same location, a BUSY pin is provided on each port. Two interrupt (INT) pins can be used for port-to-port communication. Two semaphore (SEM) control pins are used for allocating shared resources. With the M/S pin, the CY7C024E/CY7C0241E and CY7C025E/CY7C0251E can function as a master (BUSY pins are outputs) or as a slave (BUSY pins are inputs). The CY7C024E/CY7C0241E and CY7C025E/CY7C0251E have an automatic power-down feature controlled by CE. Each port is provided with its own output enable control (OE), which allows data to be read from the device.

Functional Description

Write Operation

Data must be set up for a duration of t_{SD} before the rising edge of R/W to guarantee a valid write. A write operation is controlled by either the R/W pin (see Figure 7) or the CE pin (see Figure 8). Required inputs for non-contention operations are summarized in Table 1.

If a location is being written to by one port and the opposite port attempts to read that location, a port-to-port flowthrough delay must occur before the data is read on the output; otherwise the data read is not deterministic. Data is valid on the port t_{DDD} after the data is presented on the other port.

Read Operation

When reading the device, the user must assert both the \overline{OE} and \overline{CE} pins. Data is available t_{ACE} after \overline{CE} or t_{DOE} after \overline{OE} is asserted. If the user of the CY7C024E/CY7C0241E and CY7C025E/CY7C0251E wishes to access a semaphore flag, then the SEM pin must be asserted instead of the CE pin, and \overline{OE} must also be asserted.

Interrupts

The upper two memory locations may be used for message passing. The highest memory location (FFF for the CY7C024E/CY7C0241E, 1FFF for the CY7C025E/CY7C0251E) is the mailbox for the right port and the second-highest memory location (FFE for the CY7C024E/CY7C0241E, 1FFE for the CY7C025E/CY7C0251E) is the mailbox for the left port. When one port writes to the other port's mailbox, an interrupt is generated to the owner. The interrupt is reset when the owner reads the contents of the mailbox. The message is user-defined.

Each port can read the other por<u>t's mailbox</u> without resetting the interrupt. The active state of the BUSY signal (to a port) prevents the por<u>t from</u> setting the interrupt to the winning port. Also, an active BUSY to a port prevents that port from reading its own mailbox and thus resetting the interrupt to it.

If your application does not require message passing, do not connect the interrupt pin to the processor's interrupt request input pin.

The operation of the interrupts and their interaction with Busy are summarized in Table 2 on page 8.

Busy

The CY7C024E/CY7C0241E and CY7C025E/CY7C0251E provide on-chip arbitration to resolve simultaneous memory location access (contention). If both ports' $\overline{\text{CEs}}$ are asserted and an address match occurs within t_{PS} of each other, the busy logic determines which port has access. If t_{PS} is violated, one port definitely gains permission to the location, but which one is not predictable. BUSY is asserted t_{BLA} after an address match or t_{BLC} after CE is taken LOW.

Master/Slave

A M/S pin is provided to expand the word width by configuring the device as either a master or a slave. The BUSY output of the master is connected to the BUSY input of the slave. This allows the device to interface to a master device with no external components. Writing to slave devices must be delayed until after the BUSY input has settled (t_{BLC} or t_{BLA}). Otherwise, the slave chip may begin a write cycle during a contention situation. When tied HIGH, the M/S pin allows the device to be used as a master and, therefore, the BUSY line is an output. BUSY can then be used to send the arbitration outcome to a slave.

Semaphore Operation

The CY7C024E/CY7C0241E and CY7C025E/CY7C0251E provide eight semaphore latches, which are separate from the dual-port memory locations. Semaphores are used to reserve resources that are shared between the two ports. The state of the semaphore indicates that a resource is in use. For example, if the left port wants to request a given resource, it sets a latch by writing a zero to a semaphore location. The left port then verifies its success in setting the latch by reading it. After writing to the semaphore, SEM or OE must be deasserted for tSOP before attempting to read the semaphore. The semaphore value is available $t_{SWRD} + t_{DOE}$ after the rising edge of the semaphore write. If the left port was successful (reads a zero), it assumes control of the shared resource, otherwise (reads a one) it assumes the right port has control and continues to poll the semaphore. When the right side has relinquished control of the semaphore (by writing a one), the left side succeeds in gaining control of the semaphore. If the left side no longer requires the semaphore, a one is written to cancel its request.

Semaphores are accessed by asserting SEM LOW. The SEM pin functions as a chip select for the semaphore latches (CE must remain HIGH during SEM LOW). A0–2 represents the semaphore address. OE and R/W are used in the same manner as a normal memory access. When writing or reading a semaphore, the other address pins have no effect.



When writing to the semaphore, only I/O_0 is used. If a zero is written to the left port of an available semaphore, a one appears at the same semaphore address on the right port. That semaphore can now only be modified by the side showing zero (the left port in this case). If the left port now relinquishes control by writing a one to the semaphore, the semaphore is set to one for both sides. However, if the right port had requested the semaphore (written a zero) while the left port had control, the right port immediately owns the semaphore as soon as the left

port releases it. Table 3 on page 8 shows sample semaphore operations.

When reading a semaphore, all 16/18 data lines output the semaphore value. The read value is latched in an output register to prevent the semaphore from changing state during a write from the other port. If both ports attempt to access the semaphore within t_{SPS} of each other, the semaphore is definitely obtained by one side or the other, but there is no guarantee which side controls the semaphore.

		In	puts			Ou	tputs	Operation
CE	R/W	OE	UB	LB	SEM	I/O ₀ I/O ₇ ^[9]	I/O ₈ -I/O ₁₅ ^[10]	Operation
Н	Х	Х	Х	Х	Н	High Z	High Z	Deselected: power-down
Х	Х	Х	Н	Н	Н	High Z	High Z	Deselected: power-down
L	L	Х	L	Н	Н	High Z	Data in	Write to upper byte only
L	L	Х	Н	L	Н	Data in	High Z	Write to lower byte only
L	L	Х	L	L	Н	Data in	Data in	Write to both bytes
L	Н	L	L	Н	Н	High Z	Data out	Read upper byte only
L	Н	L	Н	L	Н	Data out	High Z	Read lower byte only
L	Н	L	L	L	Н	Data out	Data out	Read both bytes
Х	Х	Н	Х	Х	Х	High Z	High Z	Outputs disabled
Н	Н	L	Х	Х	L	Data out	Data out	Read data in semaphore flag
Х	Н	L	Н	Н	L	Data out	Data out	Read data in semaphore flag
Н		Х	Х	Х	L	Data in	Data in	Write D _{IN0} into semaphore flag
Х		Х	Н	Н	L	Data in	Data in	Write D_{IN0} into semaphore flag
L	Х	Х	L	Х	L			Not allowed
L	Х	Х	Х	L	L			Not allowed

Table 1. Non-Contending Read/Write

Notes

9. $I/O_0 - I/O_8$ on the CY7C0241E/CY7C0251E. 10. $I/O_9 - I/O_{17}$ on the CY7C0241E/CY7C0251E.



Table 2. Interrupt Operation Example (Assumes $\overline{BUSY}_{L} = \overline{BUSY}_{R} = HIGH)^{[11]}$

Function			Left Po	ort		Right Port				
Function	R/₩ _L		OEL	A _{0L-11L}	INTL	R/W _R	CER	OER	A _{0R-11R}	INT _R
Set right INT _R flag	L	L	Х	(1)FFF	Х	Х	Х	Х	Х	L ^[12]
Reset right INT _R flag	Х	Х	Х	Х	Х	Х	L	L	(1)FFF	H ^[13]
Set left INT _L flag	Х	Х	Х	Х	L ^[13]	L	L	Х	(1)FFE	Х
Reset left INT _L flag	Х	L	L	(1)FFE	H ^[12]	Х	Х	Х	Х	Х

Table 3. Semaphore Operation Example

Function	I/O ₀ -I/O _{15/17} Left	I/O ₀ I/O _{15/17} Right	Status
No action	1	1	Semaphore-free
Left port writes 0 to semaphore	0	1	Left port has semaphore token
Right port writes 0 to semaphore	0	1	No change. Right side has no write access to semaphore.
Left port writes 1 to semaphore	1	0	Right port obtains semaphore token
Left port writes 0 to semaphore	1	0	No change. Left port has no write access to semaphore
Right port writes 1 to semaphore	0	1	Left port obtains semaphore token
Left port writes 1 to semaphore	1	1	Semaphore-free
Right port writes 0 to semaphore	1	0	Right port has semaphore token
Right port writes 1 to semaphore	1	1	Semaphore-free
Left port writes 0 to semaphore	0	1	Left port has semaphore token
Left port writes 1 to semaphore	1	1	Semaphore-free

11. A_{0L-12L} and A_{0R-12R}, 1FFF/1FFE for the CY7C025E/CY7C0251E.
12. If <u>BUSY</u>_L=L, then no change.
13. If <u>BUSY</u>_R=L, then no change.



Maximum Ratings

Exceeding maximum ratings may shorten the useful life of the device. User guidelines are not tested. $\ensuremath{^{[14]}}$

Storage temperature65 °C to +150 °C
Ambient temperature with power applied–55 °C to +125 °C
Supply voltage to ground potential–0.3 V to +7.0 V
DC voltage applied to outputs in high Z state0.5 V to +7.0 V

DC input voltage ^[15]	–0.5 V to +7.0 V
Output current into outputs (LOW)	
Static discharge voltage (per MIL-STD-883, Method 3015)	> 2001 V
Latch-up current	> 200 mA

Operating Range

Range	Ambient Temperature	V _{CC}
Commercial	0 °C to +70 °C	$5 \text{ V} \pm 10\%$
Industrial	–40 °C to +85 °C	$5 \text{ V} \pm 10\%$

Electrical Characteristics

Over the Operating Range

Parameter	Description	Test Conditions			-15			-25			-55		
Farameter	Description	I I I I I I I I I I I I I I I I I I I		Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit
V _{OH}	Output HIGH voltage	V _{CC} = Min, I _{OH} = -4.0 mA		2.4	-	-	2.4	-	-	2.4	-	-	V
V _{OL}	Output LOW voltage	V _{CC} = Min, I _{OL} = 4.0 mA		-	-	0.4	-	-	0.4	-	-	0.4	V
V _{IH}	Input HIGH voltage			2.2	-	-	2.2	-	-	2.2	-	-	V
V _{IL}	Input LOW voltage			-	-	0.8		-	0.8	-	—	0.8	V
I _{IX}	Input leakage current	$GND \le V_I \le V_{CC}$		-10	-	+10	-10	-	+10	-10	-	+10	μA
I _{OZ}	Output leakage current	Output disabled, GND $\leq V_O \leq V_{CC}$		-10	-	+10	-10	-	+10	-10	-	+10	μΑ
I _{CC}	Operating current	$V_{CC} = Max, I_{OUT} = 0 mA,$	Commercial	-	190	285	-	170	250	-	150	230	mA
		Outputs Disabled	Industrial	-	215	305	-	180	290	-	180	290	
I _{SB1}	Standby current	\overline{CE}_{L} and $\overline{CE}_{R} \ge V_{IH}$, f = f _{MAX} ^[16]	Commercial	-	50	70	-	40	60	-	20	50	mA
	(both ports TTL levels)	$f = f_{MAX}^{[10]}$	Industrial	-	65	95	-	55	80	1	55	80	
I _{SB2}	Standby current (one port TTL level)	\overline{CE}_{L} or $\overline{CE}_{R} \ge V_{IH}$,	Commercial	-	120	180	-	100	150	-	75	135	mA
	(one port 11L level)	$f = f_{MAX}^{I I O J}$	Industrial	-	135	205	-	120	175	-	120	175	
I _{SB3}	Standby current	Both Ports \overline{CE} and $\overline{CE}_R \ge$	Commercial	-	0.05	0.5	-	0.05	0.50	-	0.05	0.50	mA
	(both ports CMOS levels)		Industrial	-	0.05	0.5	-	0.05	0.50	-	0.05	0.50	
I _{SB4}	Standby current	One Port CEL or	Commercial	-	110	160	-	90	130	-	70	120	mA
	(both ports CMOS levels)	$\begin{array}{l} CE_R \geq V_{CC} - \bar{0.2} \text{ V}, \\ V_{IN} \geq V_{CC} - 0.2 \text{ V or } V_{IN} \leq 0.2 \text{ V}, \\ \text{Active Port Outputs, } f = f_{MAX}^{[16]} \end{array}$	Industrial	-	125	175	Ι	110	150	_	110	150	

^{14.} The voltage on any input or I/O pin cannot exceed the power pin during power-up.

^{15.} Pulse width < 20 ns.

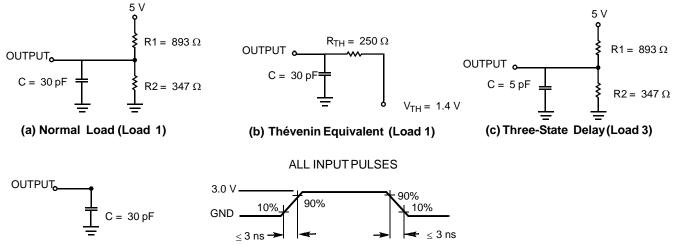
^{16.} f_{MAX} = 1/t_{RC} = All inputs cycling at f = 1/t_{RC} (except output enable). f = 0 means no address or control lines change. This applies only to inputs at CMOS level standby I_{SB3}.



Capacitance

Parameter ^[17]	Description	Test Conditions	Max	Unit
C _{IN}	Input capacitance	$T_A = 25 \degree C$, f = 1 MHz,	10	pF
C _{OUT}	Output capacitance	$V_{CC} = 5.0 V$	10	pF





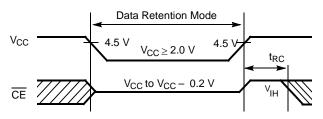
Load (Load 2)

Data Retention Mode

The CY7C024E/CY7C0241E is designed with battery backup in mind. Data retention voltage and supply current are guaranteed over temperature. The following rules insure data retention:

- 1. Chip enable (\overline{CE}) must be held HIGH during data retention, within V_{CC} to $V_{CC}-0.2$ V.
- 2. $\overline{\text{CE}}$ must be kept between V_{CC} 0.2 V and 70% of V_{CC} during the power up and power down transitions.
- 3. The RAM can begin operation $>t_{RC}$ after V_{CC} reaches the minimum operating voltage (4.5 V).

Data Retention Timing



Parameter	Test Conditions ^[18]	Max	Unit
ICC _{DR1}	At VCC _{DR} = 2 V	1.5	mA

Note

17. Tested initially and after any design or process changes that may affect these parameters. 18. $\overrightarrow{CE} = V_{CC}$, $V_{in} = GND$ to V_{CC} , $T_A = 25^{\circ}C$. This parameter is guaranteed but not tested.



Switching Characteristics

Over the Operating Range

Parameter ^[19]	Description		15	-25			55	Unit
Parameter	Description	Min	Max	Min	Max	Min	Max	
Read Cycle								
t _{RC}	Read cycle time	15	_	25	-	55	-	ns
t _{AA}	Address to data valid	-	15	-	25	-	55	ns
t _{OHA}	Output hold from address change	3	-	3	-	3	-	ns
t _{ACE} ^[20]	CE LOW to data valid	-	15	-	25	-	55	ns
t _{DOE}	OE LOW to data valid	_	10	-	13	_	25	ns
t _{LZOE} [21, 22, 23]	OE low to low Z	3	-	3	_	3	-	ns
[21, 22, 23] HZOE	OE HIGH to high Z	-	10	-	15	-	25	ns
t _{LZCE} [21, 22, 23]	CE LOW to low Z	3	-	3	-	3	-	ns
t _{HZCE} ^[21, 22, 23]	CE HIGH to High Z	_	10	-	15	_	25	ns
t _{PU} ^[23]	CE LOW to power-up	0	-	0	-	0	-	ns
t _{PD} ^[23]	CE HIGH to power-down	_	15	-	25	_	55	ns
t _{ABE} ^[20]	Byte enable access time	-	15	-	25	-	55	ns
Write Cycle		•				•		•
t _{WC}	Write cycle time	15	-	25	-	55	-	ns
t _{SCE} ^[20]	CE LOW to write end	12	-	20	-	35	-	ns
t _{AW}	Address setup to write end	12	-	20	-	35	-	ns
t _{HA}	Address hold from write end	0	-	0	-	0	-	ns
t _{SA} ^[24]	Address setup to write start	0	-	0	-	0	-	ns
t _{PWE}	Write pulse width	12	-	20	-	35	-	ns
t _{SD}	Data setup to write end	10	-	15	-	20	-	ns
t _{HD}	Data hold from write end	0	-	0	-	0	-	ns
t _{HZWE} [25, 26]	R/\overline{W} LOW to high Z	-	10	-	15	-	25	ns
t _{LZWE} [25, 26]	R/W HIGH to low Z	3	-	3	-	3	-	ns
t _{WDD} ^[27]	Write pulse to data delay	_	30	-	50	_	70	ns
t _{DDD} ^[27]	Write data valid to read data valid	_	25	_	35	_	45	ns

Notes

19. Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5 V, input pulse levels of 0 to 3.0 V, and output loading of the specified I_O/I_{OH} and 30 pF load capacitance.
20. To access RAM, CE=L, UB=L, SEM=H. To access semaphore, CE=H and SEM=L. Either condition must be valid for the entire t_{SCE} time.
21. At any given temperature and voltage condition for any given device, t_{HZCE} is less than t_{LZCE} and t_{HZOE} is less than t_{LZOE}.
22. Test conditions used are Load 3.
23. The temperature of the test is the test in the test is the test in the test is the test in the test is the test.

22. Test conditions used are Load 3.
23. This parameter is guaranteed but not tested.
24. To access RAM, CE=L, UB=L, SEM=H. To access semaphore, CE=H and SEM=L. Either condition must be valid for the entire t_{SCE} time.
25. Test conditions used are Load 3.
26. This parameter is guaranteed but not tested.

26. This parameter is guaranteed but not tested.

27. For information on port-to-port delay through RAM cells from writing port to reading port, refer to Figure 11 on page 16.



Switching Characteristics (continued)

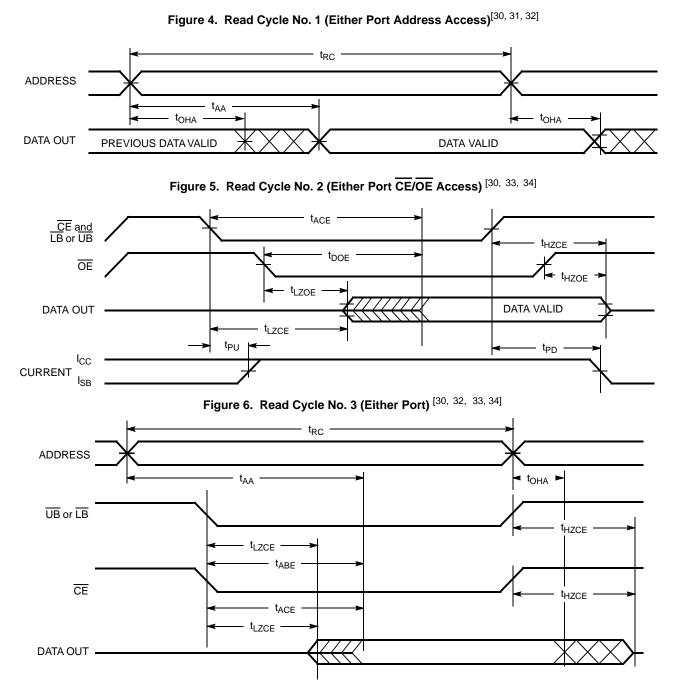
Over the Operating Range

Parameter ^[19]	Description	-	15	-25		-55		Unit
Farameter	Description	Min	Max	Min	Max	Min	Max	Unit
Busy Timing ^{[2}	8]		·					
t _{BLA}	BUSY LOW from Address Match	-	15	-	20	_	45	ns
t _{BHA}	BUSY HIGH from Address Mismatch	-	15	-	20	-	40	ns
t _{BLC}	BUSY LOW from CE LOW	-	15	-	20	_	40	ns
t _{BHC}	BUSY HIGH from CE HIGH	_	15	_	20	_	35	ns
t _{PS}	Port Setup for Priority	5	-	5	-	5	-	ns
t _{WB}	R/\overline{W} HIGH after \overline{BUSY} (Slave)	0	-	0	-	0	-	ns
t _{WH}	R/\overline{W} HIGH after \overline{BUSY} HIGH (Slave)	13	-	20	-	40	-	ns
t _{BDD} ^[29]	BUSY HIGH to Data Valid		Note 29		Note 29		Note 29	ns
Interrupt Timi	ng ^[28]							
t _{INS}	INT Set Time	_	15	_	20	_	30	ns
t _{INR}	INT Reset Time	-	15	-	20	-	30	ns
Semaphore Ti	ming							
t _{SOP}	SEM Flag Update Pulse (\overline{OE} or \overline{SEM})	10	-	12	_	20	-	ns
t _{SWRD}	SEM Flag Write to Read Time	5	-	10	-	15	-	ns
t _{SPS}	SEM Flag Contention Window		-	10	-	15	-	ns
t _{SAA}	SEM Address Access Time	_	15		25	—	55	ns

Notes 28. Test conditions used are Load 2. 29. t_{BDD} is a calculated parameter and is the greater of t_{WDD} – t_{PWE} (actual) or t_{DDD} – t_{SD} (actual).



Switching Waveforms



- 30. R/W is HIGH for read cycles. 31. Device is continuously selected $\overline{CE} = V_{IL}$ and \overline{UB} or $\overline{LB} = V_{IL}$. This waveform cannot be used for semaphore reads.

- 32. $\overrightarrow{OE} = V_{IL}$ 33. Address valid prior to or coincident with \overrightarrow{CE} transition LOW. 34. To access RAM, $\overrightarrow{CE} = V_{IL}$, \overrightarrow{UB} or $\overrightarrow{LB} = V_{IL}$, $\overrightarrow{SEM} = V_{IL}$. To access semaphore, $\overrightarrow{CE} = V_{IH}$, $\overrightarrow{SEM} = V_{IL}$.



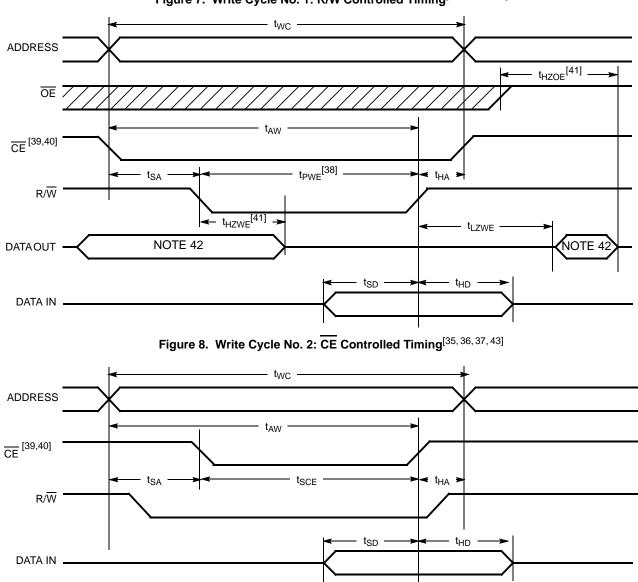


Figure 7. Write Cycle No. 1: R/W Controlled Timing^[35, 36, 37, 38]

- 35. R/W must be HIGH during all address transitions.
- 36. A write occurs during the overlap (t_{SCE} or t_{PWE}) of a LOW <u>CE</u> or <u>SEM</u> and a LOW <u>UB</u> or <u>LB</u>.
 37. t_{HA} is measured from the earlier of CE or RW or (SEM or RW) going HIGH at the end of write cycle.
- 37. H_{HA} Is measured from the earlier of CE of R/W of (SEM of R/W) going HIGH at the end of write cycle.
 38. If OE is LOW during a R/W controlled write cycle, the write pulse width must be the larger of t_{PWE} or (t_{HZWE} + t_{SD}) to allow the I/O drivers to turn off and data to be placed on the bus for the required t_{SD}. If OE is HIGH during an R/W controlled write cycle, this requirement does not apply and the write pulse can be as short as the specified t_{PWE}.
 39. To access RAM, CE = V_{IL}, SEM = V_{IL}.
 40. To access upper byte. CE = V_{IL}, UB = V_{IL}. SEM = V_{IH}.
 To access lower byte, CE = V_{IL}, UB = V_{IL}.
 41. Togenerate the state of the pulse during the transition is measured at the state write the target of the pulse.

- 41. Transition is measured ±500 mV from steady state with a 5 pF load (including scope and jig). This parameter is sampled and not 100% tested.
- 42. During this period, the I/O pins are in the output state, and input signals must not be applied. 43. If the CE or SEM LOW transition occurs simultaneously with or after the RW LOW transition, the outputs remain in the high impedance state.



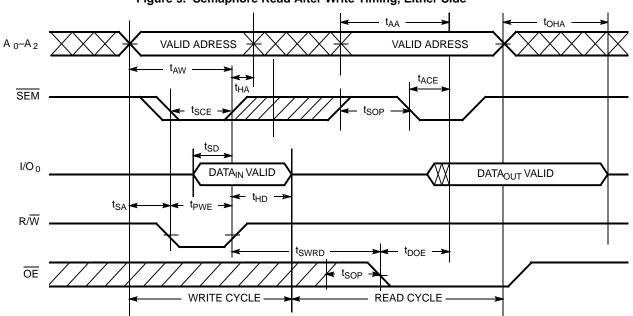
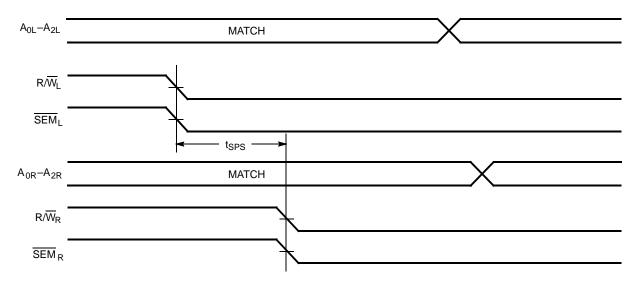


Figure 9. Semaphore Read After Write Timing, Either Side^[44]

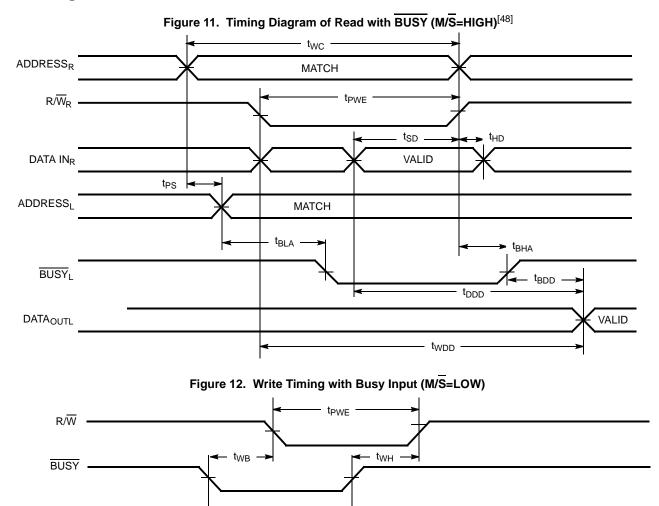
Figure 10. Timing Diagram of Semaphore Contention^[45, 46, 47]



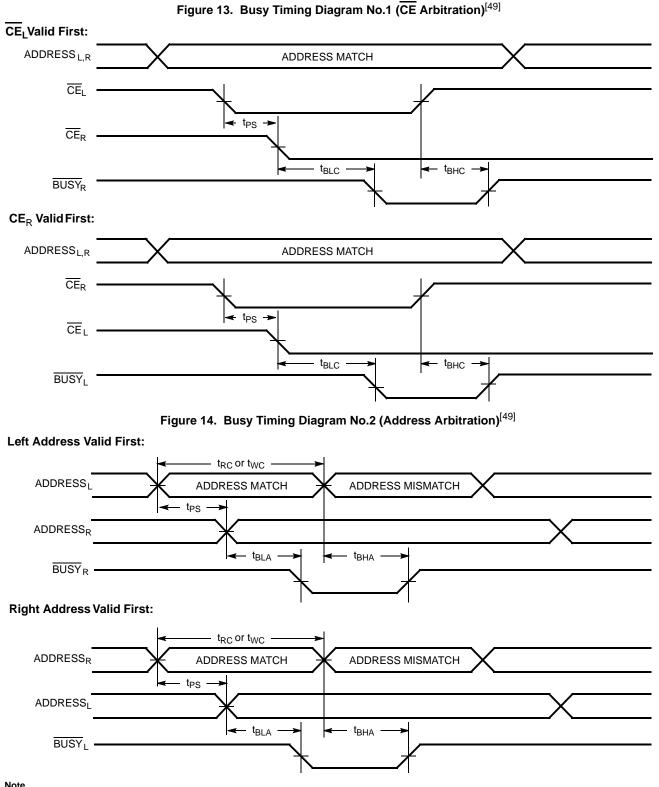
- 44. CE = HIGH for the duration of the above timing (both write and read cycle).
- 45. $I/O_{0R} = I/O_{0L} = LOW (request semaphore); CE_R = CE_L = HIGH.$ 46. Semaphores are reset (available to both ports) at cycle start.

^{47.} If t_{SPS} is violated, the semaphore is definitely obtained by one side or the other, but which side gets the semaphore is unpredictable.









Note

49. If t_{PS} is violated, the busy signal is asserted on one side or the other, but there is no guarantee to which side BUSY is asserted.



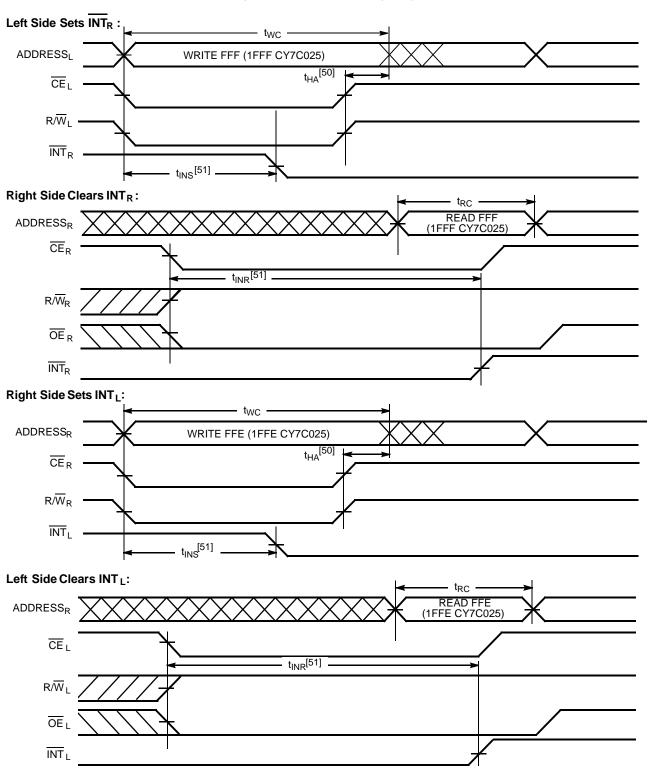


Figure 15. Interrupt Timing Diagrams

Notes

50. t_{HA} depends on which enable pin (\overline{CE}_L or \overline{RW}_L) is deasserted first. 51. t_{INS} or t_{INR} depends on which enable pin (\overline{CE}_L or \overline{RW}_L) is asserted last.



Ordering Information

4 K × 16 Dual-Port SRAM

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
15	CY7C024E-15AXC	A100	100-pin TQFP (Pb-free)	Commercial
25	CY7C024E-25AXC	A100	100-pin TQFP (Pb-free)	Commercial
	CY7C024E-25AXI	A100	100-pin TQFP (Pb-free)	Industrial
55	CY7C024E-55AXC	A100	100-pin TQFP (Pb-free)	Commercial

8 K × 16 Dual-Port SRAM

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
25	CY7C025E-25AXC	A100	100-pin TQFP (Pb-free)	Commercial
	CY7C025E-25AXI	A100	100-pin TQFP (Pb-free)	Industrial
55	CY7C025E-55AXC	A100	100-pin TQFP (Pb-free)	Commercial

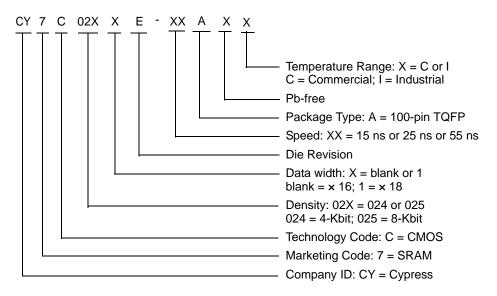
4 K × 18 Dual-Port SRAM

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
25	CY7C0241E-25AXC	A100	100-pin TQFP (Pb-free)	Commercial

8 K × 18 Dual-Port SRAM

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
15	CY7C0251E-15AXC	A100	100-pin TQFP (Pb-free)	Commercial

Ordering Code Definitions





CY7C024E/CY7C0241E CY7C025E/CY7C0251E

Package Diagrams

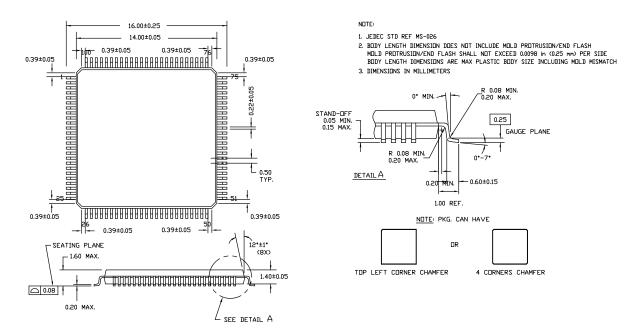


Figure 16. 100-pin TQFP (14 × 14 × 1.4 mm) A100SA Package Outline, 51-85048

51-85048 *H



Acronyms

Acronym	Description			
CE	Chip Enable			
CMOS	Complementary Metal Oxide Semiconductor			
I/O	Input/Output			
OE	Output Enable			
SRAM	Static Random Access Memory			
TQFP	Thin Quad Flat Pack			

Document Conventions

Units of Measure

Symbol	Unit of Measure			
°C	degree Celsius			
MHz	megahertz			
μA	microampere			
mA	milliampere			
ns	nanosecond			
Ω	ohm			
%	percent			
pF	picofarad			
V	volt			
W	watt			



Document History Page

INT, BUSY	Title: CY7C0 Number: 00 ⁴		241E/CY7C025	$E/CY7C0251E, 4$ K \times 16/18 and 8 K \times 16/18 Dual-Port Static RAM with SEM,
Rev.	ECN No.	Orig. of Change	Submission Date	Description of Change
**	2975554	RAME	07/09/2010	New data sheet.
*A	3056347	ADMU	10/28/2010	Updated "Selection Guide" on page 1: For speed bin -25: Typical Operating current(mA) changed from 180 to 170, Typical standby current for ISB1 (mA) changed from 45 to 40 For speed bin -55: Typical Operating current(mA) changed from 180 to 150, Typical standby current for ISB1 (mA) changed from 45 to 20. Updated "Electrical Characteristics" on page 9: The values for the speed bins -25 and -55 have been put into separate columns. The values for Commercial parts have been modified for the following parameters: (no degradation of spec). Operating Current ICC: "180(typ) / 275(max)" changed to "170(typ) / 250(max) for speed bin -25" and "150(typ) / 230(max) for speed bin -55" Standby Current ISB1 (both ports TTL levels): "45(typ) / 65(max)" changed to "40(typ) / 60(max) for speed bin -25", and "20(typ) / 50(max) for speed bin -55" Standby Current ISB2 (one port TTL level) : "110(typ) / 160(max)" changed to "100(typ) / 150(max) for speed bin -25", and "75(typ) / 135(max) for speed bin -55" Standby Current ISB4 (both ports CMOS Levels) : "100(typ) / 140(max)"
				changed to "90(typ) / 130(max) for speed bin -25", and "70(typ) / 120(max) for speed bin -55" Updated "4 K × 18 Dual-Port SRAM" on page 19: Removed part CY7C0241E - 55AXI from ordering information.
*В	3247559	ADMU	05/04/2011	Removed VIL min rating for all speed bins. Updated Ordering Code Definition details. Updated Package Diagrams.
*C	3864478	ADMU	01/10/2013	Updated Ordering Information (Updated part numbers). Updated Package Diagrams: spec 51-85048 – Changed revision from *E to *G.
*D	4075480	ADMU	07/24/2013	Updated Logic Block Diagram. Updated Pin Configurations. Updated in new template. Completing Sunset Review.
*E	4093991	ADMU	08/13/2013	Updated Package Diagrams: spec 51-85048 – Changed revision from *G to *H. Added Units of Measure.



Sales, Solutions, and Legal Information

Worldwide Sales and Design Support

Cypress maintains a worldwide network of offices, solution centers, manufacturer's representatives, and distributors. To find the office closest to you, visit us at Cypress Locations.

cypress.com/go/automotive
cypress.com/go/clocks
cypress.com/go/interface
cypress.com/go/powerpsoc
cypress.com/go/plc
cypress.com/go/memory
cypress.com/go/psoc
cypress.com/go/touch
cypress.com/go/USB
cypress.com/go/wireless

PSoC[®] Solutions

psoc.cypress.com/solutions PSoC 1 | PSoC 3 | PSoC 4 | PSoC 5LP

Cypress Developer Community Community | Forums | Blogs | Video | Training

Technical Support cypress.com/go/support

© Cypress Semiconductor Corporation, 2010-2013. The information contained herein is subject to change without notice. Cypress Semiconductor Corporation assumes no responsibility for the use of any circuitry other than circuitry embodied in a Cypress product. Nor does it convey or imply any license under patent or other rights. Cypress products are not warranted nor intended to be used for medical, life support, life saving, critical control or safety applications, unless pursuant to an express written agreement with Cypress. Furthermore, Cypress does not authorize its products for use as critical components in life-support systems where a malfunction or failure may reasonably be expected to result in significant injury to the user. The inclusion of Cypress products in life-support systems application implies that the manufacturer assumes all risk of such use and in doing so indemnifies Cypress against all charges.

Any Source Code (software and/or firmware) is owned by Cypress Semiconductor Corporation (Cypress) and is protected by and subject to worldwide patent protection (United States and foreign), United States copyright laws and international treaty provisions. Cypress hereby grants to licensee a personal, non-exclusive, non-transferable license to copy, use, modify, create derivative works of, and compile the Cypress Source Code and derivative works for the sole purpose of creating custom software and or firmware in support of licensee product to be used only in conjunction with a Cypress integrated circuit as specified in the applicable agreement. Any reproduction, modification, translation, compilation, or representation of this Source Code except as specified above is prohibited without the express written permission of Cypress.

Disclaimer: CYPRESS MAKES NO WARRANTY OF ANY KIND, EXPRESS OR IMPLIED, WITH REGARD TO THIS MATERIAL, INCLUDING, BUT NOT LIMITED TO, THE IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A PARTICULAR PURPOSE. Cypress reserves the right to make changes without further notice to the materials described herein. Cypress does not assume any liability arising out of the application or use of any product or circuit described herein. Cypress does not authorize its products for use as critical components in life-support systems where a malfunction or failure may reasonably be expected to result in significant injury to the user. The inclusion of Cypress' product in a life-support systems application implies that the manufacturer assumes all risk of such use and in doing so indemnifies Cypress against all charges.

Use may be limited by and subject to the applicable Cypress software license agreement.

Document Number: 001-62932 Rev. *E

Revised August 13, 2013

All products and company names mentioned in this document may be the trademarks of their respective holders.